

**Amendments to the Claims:**

This listing of claims will replace all prior versions, and listings of claims in the application:

**Listing of Claims:**

1-17. (Canceled)

18. (Currently amended) A method of classifying defects, comprising the steps of:

~~determining, for each defect classification class of a first defect classifier for a first inspection machine,~~ a sampling rate of defects to be ~~sampled and detected~~ reviewed by a second inspection machine among defects detected ~~when an inspection sample is inspected by~~ [[the]] a first inspection machine; and

~~detecting, by reviewing with said second inspection machine, defects sampled from said~~ defects detected ~~when a sample targeted for inspection is inspected by said first inspection machine~~ [[,]] in accordance with said determined sampling rate ~~for said each defect class,~~ and classifying said ~~detected~~ reviewed defects with a second defect classifier corresponding to said second inspection machine;

wherein the step of determining, said sampling rate is determined for each of defect classes classified by a first defect classifier corresponding to said first inspection machine. ~~for each defect classification class of a first defect classifier corresponding to said first inspection machine, said rate of defects to be sampled and detected by said second inspection machine comprises the sub-steps of:~~

~~inspecting said inspection sample with said first inspection machine;~~  
~~classifying defects of said inspection sample inspected and detected by the first inspection machine with said first defect classifier;~~

~~detecting defects of said inspection sample detected by said first inspection machine with a second inspection machine;~~

22 ~~classify said defects of said inspection sample detected by the second defect~~  
23 ~~inspection machine with said second defect classifier; and~~  
24 ~~determining, for said each defect classification class, said sampling rate for~~  
25 ~~defects that are detected by said first inspection machine and classified by said first defect~~  
26 ~~classifier in accordance with a relationship between the classification class of the defects in said~~  
27 ~~inspection sample classified with said first defect classifier and the classification class of the~~  
28 ~~defects in said inspection sample classified with said second defect classifier.~~

1 19. (Original) The method according to claim 18, wherein said second defect  
2 classifier has a decision tree for hierarchically expanding defect classification class elements via  
3 branch elements, and wherein said decision tree is such that a classification rule created with  
4 sample inspection information that has been previously derived from an inspection of an  
5 inspection sample is individually set for each of said branch elements.

1 20. (Currently amended) The method according to claim 19, wherein said  
2 individual classification rule that is set for each of said branch elements in said second defect  
3 classifier is set on a screen that displays said sample inspection information derived from said  
4 inspection of said inspection sample.

1 21. (Currently amended) A method of classifying defects, comprising the  
2 steps of:  
3 determining a sampling rate of defects to be ~~sampled and detected~~ reviewed by a  
4 second inspection machine among defects detected by a first inspection machine; and  
5 ~~detecting reviewing~~, with said second inspection machine, defects sampled from  
6 said defects detected ~~when a sample targeted for inspection is inspected~~ by said first inspection  
7 machine[[,]] in accordance with said determined sampling rate ~~for each defect class~~, and  
8 classifying the ~~detected~~ reviewed defects with a second defect classifier corresponding to said  
9 second inspection machine;

10 wherein the step of determining, ~~determining said rate of defects to be sampled~~  
11 ~~and detected by said second inspection machine comprises the sub-steps of:~~

12                           ~~inspecting an inspection sample with a first inspection machine;~~  
13                           ~~classifying the defects inspected and detected by the first inspection~~  
14 ~~machine with a first defect classifier; and~~  
15                           determining a said sampling rate of defects sampled to be reviewed by  
16 said second inspection machine is determined for each defect ~~classification~~ class in accordance  
17 with reliability of ~~classification~~ to each ~~classification~~ defect class of defects classified with  
18 ~~[[said]] a first defect classifier for said each defect classification class~~ corresponding to said first  
19 inspection machine.

1                           22.     (Original) The method according to claim 21, wherein said second defect  
2 classifier has a decision tree for hierarchically expanding defect classification class elements via  
3 branch elements, and wherein said decision tree is such that a classification rule created with  
4 sample inspection information that has been previously derived from an inspection of an  
5 inspection sample is individually set for each of said branch elements.

1                           23.     (Currently amended) The method according to claim ~~[[19]]~~ 22, wherein  
2 said classification rule that is individually set for each of said branch elements in said classifier is  
3 set ~~[[from]]~~ on a screen that displays sample inspection information derived from an inspection  
4 of said inspection sample.